

Notice of References Cited

Application/Control No.

09/464,322

Applicant(s)/Patent Under
Reexamination
KWON ET AL.

Examiner

Chris C. Chu

Art Unit

2815

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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